

# V3000 Macro-Scope Inspection System

## Smart Solutions for the Semiconductor Industry



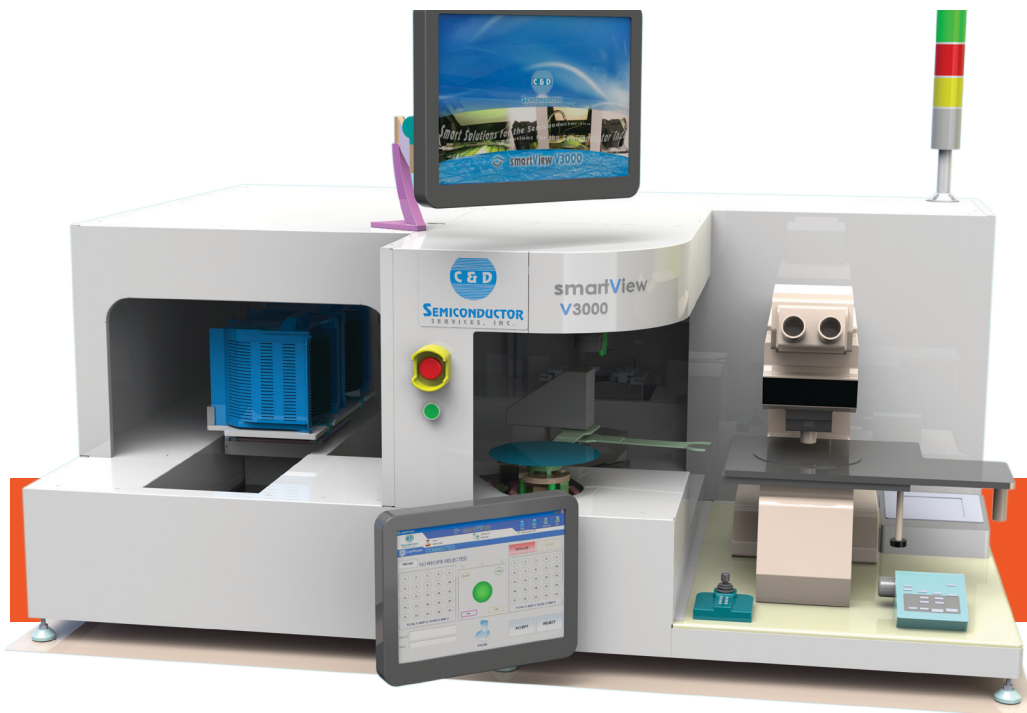
## Introducing The V3000 Macro-Scope Inspection System

— A Powerful, Innovative, One-Stop Wafer Inspection Solution for the Semiconductor Industry

C&D Semiconductor is proud to announce its latest technology innovation — the V3000 Macro-Scope Inspection System!

The V3000 Macro-Scope Inspection System provides an advanced wafer inspection solution that incorporates all procedures of the wafer inspection process into one powerful, easy-to-use, automated system. It combines the capabilities of bright light macro inspection and microscope inspection systems, making it possible to handle wafer-loading/unloading, transfer, and macro-/micro-inspections on one integrated system. It offers great performance, reliability, energy efficiency, and cost of ownership.

The V3000 Macro-Scope Inspection System features a simple, intuitive, and easy-to-operate graphical user interface. The system enables you to automate the wafer inspections via the use of custom-configured recipes, while, at the same time, also allows for the option of manual operation. This combination of automatic and manual operation modes not only ensures high productivity, but also offers great operational flexibility.



### SYSTEM FEATURES

The V3000 Macro-Scope Inspection System is able to effectively pinpoint glaring and subtle wafer defects on a wafer during macro inspection and then seamlessly move the substrate to the microscope for further and detailed inspection. **The system comes with many great features, including:**

- Four lighting sources for macro inspection
- Capable of handling 50 mm – 200 mm substrates
- Auto-bridging for different-sized substrates
- Wafer-flipping for backside inspection
- Macro inspection module with 3-axis tilt rotating gimble chuck
- Standard Leica DM8000 microscope
- Optical Character Recognition (OCR)
- SECS/GEM capable

For more information, please call (408) 383-1888.



**SEMICONDUCTOR**  
SERVICES, INC.

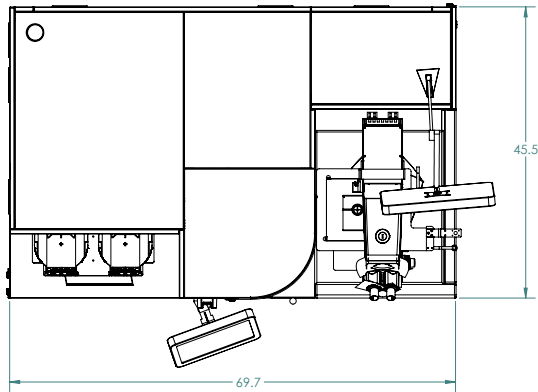


Figure 1

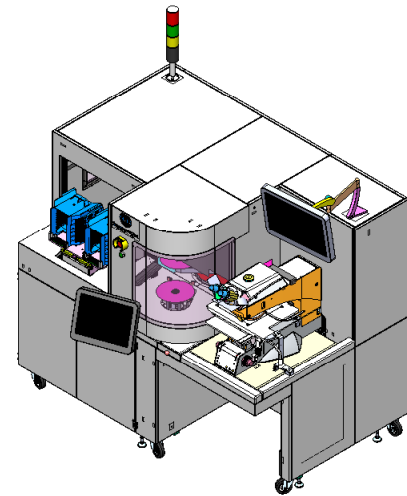


Figure 2

## V3000 Macro-Scope Inspection – Footprint

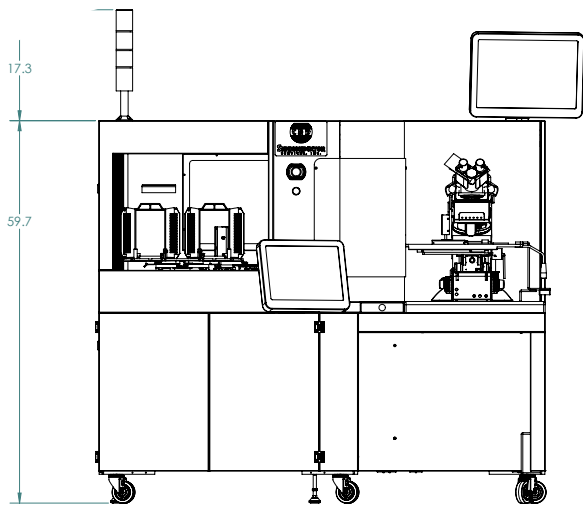


Figure 3

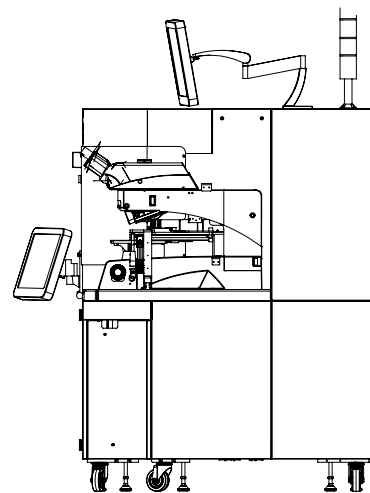


Figure 4